

In the Claims

This listing of claims will replace all prior versions and listings of claims in the application:

1 1. (Previously Amended) A method for emulation communications
2 via a test data input port and boundary-scan architecture providing
3 serial access to a serial connection of a plurality of registers
4 disposed in a plurality of modules, each of the plurality of
5 modules including at least one of the plurality of registers,
6 comprising the steps of:

7 selecting for communication one of said plurality of modules,
8 nonselected modules being nonresponsive to data on said serial
9 connection;

10 supplying to the test data input port for communication to the
11 boundary-scan architecture a serial signal having a number of bits
12 greater in number than a number of bits of the serial connection of
13 the plurality of registers, each bit of said serial signal having a
14 first digital state;

15 following supply of said serial signal, supplying to the test
16 data input port for communication to the boundary-scan architecture
17 a single start bit having a second digital state opposite to said
18 first digital state followed by a predetermined number of data
19 bits;

20 at said selected module detecting said single start bit within
21 the boundary-scan architecture and storing said predetermined
22 number of data bits.

1 2. (Original) The method of claim 1, wherein:

2 said step of storing said predetermined number of data bits
3 consists of storing said predetermined number of data bits in a
4 program visible data register.

1 3. (Original) The method of claim 1, further comprising:
2 at said selected module, interpreting said predetermined
3 number of data bits as an instruction and performing a function
4 corresponding to said instruction.

1 4. (Currently Amended) The method of claim 1, wherein the
2 boundary-scan architecture includes a test data output port
3 following a last of the serial connection of registers, the method
4 further comprising:

5 at said selected module, identifying a predetermined number of
6 data bits to be transmitted, ~~supplying a serial signal having said~~
7 ~~first digital state to following registers in the serial connection~~
8 ~~of the plurality of registers for a predetermined number of bits~~
9 and supplying to following registers in the serial connection of
10 the plurality of registers a single start bit having a second
11 digital state opposite to said first digital state followed by said
12 identified predetermined number of data bits to be transmitted.

1 5. (Previously Amended) The method of claim 1, wherein:
2 said first digital state is 1; and
3 said second digital state is 0.

1 6. (Currently Amended) A digital electronic module
2 comprising:

3 a serial scan path having a serial input and a serial output
4 and connecting through a plurality of data registers within the
5 digital electronic module;

6 a start bit detector having a start bit detector ~~input~~ input,
7 a start bit detector output and an alternative data output, said
8 start bit detector monitoring serial data received at said start
9 bit detector input and coupling serial data received at said start
10 bit detector input to said start bit detector output except upon

11 detection of a number of serial bits greater than a first
12 predetermined number having a first digital state followed by a
13 single start bit having a second digital state opposite to said
14 first digital state coupling a second predetermined number of bits
15 of serial data received at said start bit detector input to said
16 alternative data output;

17 an alternative data input register connected to said
18 alternative data output of said start bit detector for receiving
19 and storing data output by said start bit detector on said
20 alternative data output;

21 an input switch having a serial test data input and a mode
22 input, said input switch connecting said serial test data input to
23 said serial data input of said serial scan path upon receiving a
24 serial scan path mode signal at said mode input and connecting said
25 serial test data input to said serial data input of said start bit
26 detector upon receiving an alternate data transfer protocol mode
27 signal at said mode input; and

28 an output switch having a test data output and a mode input,
29 said output switch connecting said serial data output of said
30 serial scan path to said test data output upon receiving said
31 serial scan path mode signal on said mode input and connecting said
32 serial data output of said start bit detector to said test data
33 output upon receiving said alternate data transfer protocol mode
34 signal at said mode input.

1 7. (Previously Amended) The digital electronic module of
2 claim 6, wherein:
3 said first digital state is 1; and
4 said second digital state is 0.

1 8. (Previously Added) The digital electronic module of claim
2 6, further comprising:

3 a bypass path connecting said input switch and said output
4 switch;
5 said input switch further connecting said serial test data
6 input to said bypass path upon receiving a bypass path mode signal
7 at said mode input; and
8 said output switch further connecting said bypass path to said
9 test data output upon receiving said bypass path mode signal at
10 said mode input.

1 9. (Previously Added) The digital electronic module of claim
2 6, further comprising:

3 a digital circuit connected to said alternative data input
4 register operable to employ data stored in said alternative data
5 input register.

1 10. (Previously Added) The digital electronic module of claim
2 9, wherein:

3 said digital circuit includes a programmable digital processor
4 core.

1 11. (Previously Added) The digital electronic module of claim
2 10, wherein:

3 said programmable digital processor core employs data stored
4 in said alternative data input register as an instruction
5 controlling execution by said programmable digital processor core.

1 12. (Currently Amended) The digital electronic module of
2 claim 9, further comprising:

3 an alternative data output register connected to said digital
4 circuit storing data specified by said digital circuit;

5 a start bit generator connected to said alternative data
6 output register and said output switch, said start bit generator

7 ~~generating a serial signal having a predetermined number of bits,~~
8 ~~each bit of said serial signal having a first digital state,~~
9 generating a start bit having said second digital state followed by
10 a predetermined number of bits of output data stored in said
11 alternative data output register; and
12 said output switch further connecting ~~said serial signal,~~ said
13 start bit and said predetermined number of bits of output data
14 stored in said alternative data output register to said test data
15 output.
